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Application/Control No.	Applicant(s)/Patent under Reexamination		
10/072,147	HAKKARAINEN ET AL.	HAKKARAINEN	
Examiner	Art Unit	Art Unit	
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Class	Subclass	Date	Examiner
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
380/200,210-211,228-229,259- 260,262,278-279,281-282 713/155,159,172 725/30-31,62-64 (text search only, see history printout)	3/14/2007	MDD
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NPL (GOOGLE)	3/16/2007	MD
Inventor Name Search	3/16/2007	MD
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